



## 80<sup>th</sup> ARFTG Microwave Measurement Symposium

Topic: Advances in Wireless Communications Test and Measurements  
November 27<sup>th</sup> - 30<sup>th</sup>, 2012, San Diego, California – Hilton Bayfront Hotel

[www.arftg.org](http://www.arftg.org)

### Short Course on Microwave Measurements

Nov 27<sup>th</sup> 8am-5pm - Nov 28<sup>th</sup> 8am-12pm

#### Welcome and Introduction

*Patrick Roblin – The Ohio State University*

#### Principles of Power Measurement & Uncertainties

*Tom Crowley – NIST*

#### VNA Measurements & Uncertainties

*Ken Wong – Agilent*

#### On Wafer S-Parameters & Uncertainties

*Dylan Williams – NIST*

#### Microwave Noise Measurements

*Ali Boudiaf – Maury Microwave*

#### High Speed Oscilloscope Measurement Advancements

*Paul Hale – NIST*

#### Spectrum Analysis & Vector Signal Analysis

*Marcus da Silva – Tektronix*

#### Wireless Figures of Merit and Wireless Standards

*Earl McCune*

#### Characterization of Envelope Tracking PAs

*Paul Draxler – UCSD*

#### Large-Signal Measurements

*Dominique Schreurs – K.U.Leuven*

#### CW and Pulsed-RF NVNA Measurements

*Jean Pierre Teyssier – XLIM / Agilent*

#### Pulsed RF Load-pull Measurements

*Patrick Roblin – The Ohio State University*

#### Mixed-Signal Load-pull System

*Marco Spirito – TU Delft University*

### Workshop: “Design for wireless communications: from transistor to system-level characterization”

Organizer: Antonio Raffo, University of  
Ferrara, Italy

Nov 28<sup>th</sup> 1pm – 5pm

**Prof. Andrea Ferrero**, Politecnico di Torino, Italy -  
Traditional Microwave Measurements: What's Next?

**Prof. Dominique Schreurs**, K.U. Leuven, Belgium -  
Towards efficient amplifier design with non-linear  
measurements

**Dr. Peter J. Zampardi**, Skyworks - Power  
Amplifier Design and Technology: What Really  
Impacts PAE and Linearity?

**Dr. Kate A. Remley**, NIST - System-level  
characterization: conducted and over-the-air testing

### Workshop: “Measurement Techniques for RF Nanoelectronics”

Organizer: Mitch Wallis, NIST

Nov 30<sup>th</sup> 1pm – 5pm

**Peter Burke**, UC-Irvine, “Carbon nanotube  
electronics: SOA and performance projections”

**Jeong-Sun Moon**, HRL Laboratories, “An overview  
of graphene for RF applications”

**Mark Rodwell**, UC-Santa Barbara, “Measurements  
of High Frequency (THz) Devices”

**Hassan Tanbakuchi**, Agilent Technologies, “Nano-  
scale microwave characterization”

### ARFTG Conference

Nov 29<sup>th</sup> 8am-5pm - Nov 30<sup>th</sup> 8am-12pm

#### Invited Guest Speakers

**Fred Schindler**, Director at RFMD:

“Working with the Latest Wireless Devices and  
Standards “

**Dr. Kate A. Remley**, Leader of the Metrology for  
Wireless Systems Project at NIST:

“Millimeter-Wave Modulated-Signal Measurements“

**Basim Noori**, Distinguished Member of the  
Technical Staff at **Freescale Semiconductors**:

“Advances and Requirements of Next Generation  
High Power Load-Pull Systems “

**Claude Seltzer**, Associate Director at **Wireless  
Technology Center, Indiana Univ.-Purdue Univ.  
Fort Wayne**:

“High Power Nonlinear Measurements: Calibration  
Issues, Real Time Load-pull, and Other RF Data “

**Gary Simpson**, CTO at **Maury Microwave**:

“Evolution of Noise Parameters and Load-Pull  
Measurement Systems with Impedance Tuner  
Technologies “

#### **5 oral paper sessions**

#### **Poster session**

#### **Special 80<sup>th</sup> ARFTG session**

**Exhibitors from Microwave Industry  
Reception, Banquet & Entertainment**

### Registration Information:

[http://www.arftg.org/conferences/80th\\_conference.html](http://www.arftg.org/conferences/80th_conference.html)